

Title (en)
METHOD FOR IDENTIFYING SUBSTRATES WHICH ARE FAULTY OR HAVE BEEN INCORRECTLY INSERTED INTO A CVD REACTOR

Title (de)
VERFAHREN ZUM ERKENNEN FEHLERHAFTER ODER FEHLERHAFT IN EINEN CVD-REAKTOR EINGESETZTE SUBSTRATE

Title (fr)
PROCÉDÉ D'IDENTIFICATION DE SUBSTRATS DÉFECTUEUX OU INCORRECTEMENT INSÉRÉS DANS UN RÉACTEUR DE DÉPÔT CHIMIQUE EN PHASE VAPEUR

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Abstract (en)
[origin: WO2022023122A1] The invention relates to a method for identifying substrates (3) which are faulty or have been incorrectly inserted in a CVD reactor, with the aid of one or more optical sensors (3), which sense properties of the surfaces of the substrates, for example layer thickness or temperature, before or during a treatment process of the substrates (3) within the CVD reactor housing (1). The measurement values provided by the sensors (3) can be plotted in the form of a measurement curve, and patterns are obtained from the measurement curve, each pattern corresponding to one of the substrates (3). The patterns are compared with each other or with a mean (Lm) calculated from the patterns.

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